

**Amendments to the Claims**

This listing of claims will replace all prior versions and listings of claims in the subject application.

**Listing of Claims:**

What is claimed is:

1-64 (Cancelled)

65. (Previously Presented) An implant comprising:

a bone-facing distal surface;

a proximal surface; and

an outer perimeter generally disposed about said distal and said proximal surfaces comprising at least two surfaces each having a concentric arcuate shape with a common center and a first and at least a second generally opposing side surfaces extending generally along a length of said implant between said at least two arcuate shaped surfaces, wherein said outer perimeter has a truncated circular shape.

66. (Previously Presented) An implant according to claim 65, wherein said truncated circular shape comprises a circular shape truncated on two opposed sides.

67. (Cancelled)

68. (Previously Presented) An implant according to claim 65, further comprising a protrusion extending around at least a portion of said implant, said protrusion configured to cover an un-excised portion of an articular surface proximate said implant.

69. (Previously Presented) A method of mapping a surface contour of an articular surface comprising:

establishing a working axis extending from said articular surface;

providing a first probe having a first diameter;

measuring a first distance between at least a first point of said articular surface and a first plane substantially normal to said working axis at a distance substantially equal to said first diameter of said first probe from said working axis;

providing a second probe having a second diameter; and

measuring a second distance between at least a second point of said articular surface and a second plane substantially normal to said working axis at a distance substantially equal to said second diameter of said second probe from said working axis.

70. (Previously Presented) A method according to claim 69, wherein said first diameter of said first probe is larger than said second diameter of said second probe.

71. (Previously Presented) A method according to claim 69, wherein an arc-length of said articular surface between said working axis and said at least a first point is greater than an arc-length of said articular surface between said working axis and said at least a second point.

72. (New) The method of claim 69, wherein said first and said second planes are the same.

73. (New) The method of claim 69, wherein said first and said second planes are different.